





Towards Current Mapping of Photovoltaic Devices by Compressed Imaging

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Outline

- Summary of compressed sensing theory
- Application on PV spatial characterization
- Prototype experimental setup
- Initial measurements







Compressed sensing theory motivation

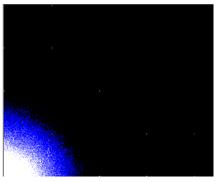
- JPEG image compression
- Sample everything (initial picture)
- Discrete Cosine Transform or Wavelet Transform (JPEG2000) sparse representation
- Compress to store as JPEG, using a small number of coefficients to save space
- Reconstruct using this small amount of coefficients

Sample





Applied PV group CREST



DCT coefficients



Reconstruction using only 2% largest DCT coefficients







Compressed sensing theory motivation

- In signal compression a huge amount of information is thrown away anyway
- Why measure it in the first place?
- Sample only a compressed version of the signal
- Reconstruct the signal (image)
- Useful in applications where measurements have a high "cost":
- Expensive detectors
- Limited time
- High sampling rate not possible

Sample

Coefficients

N pixel image - 2% used









X

Compressed sensing theory: summary

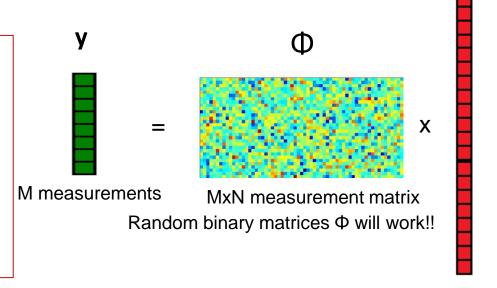
A Signal x is K sparse in basis φ (i.e. DCT domain)

Step 1

- Acquire a "condensed" representation using M < N linear measurements between ${\bf x}$ and a collection of test functions $\{\varphi_m\}_{m=1}^M$
- In other words we measure $y[m] = \langle x, \varphi_m \rangle = \Phi[m, n] x[n]$

Step 2

- Reconstruction: given y=Φx
 find x
- Infinite solutions
- · convex optimisation problem
- 1 minimisation is used to determine x
- $\hat{x} = argmin||x||_1$ subject to $y = \Phi x$
- Other norms are also used





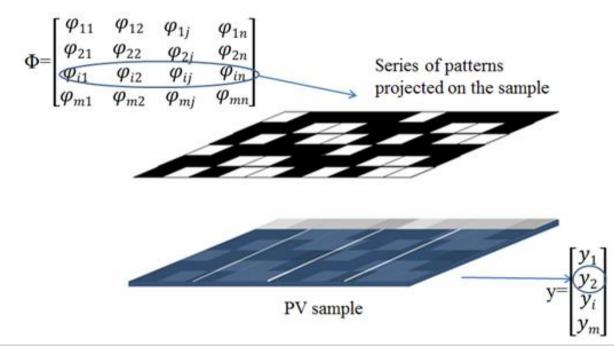




Compressed sensing: Application on PV characterisation

- For a pixel by pixel scan, Light Beam Induced Current (LBIC) measurements can last several hours for mapping the local current of a typical PV cell.
- We can reduce measurement time by making compressed measurements
- Illuminating the cell with a series of patterns which measure the necessary coefficients

- Reconstructing image using lead of the contraction of the
- Fewer measurements are needed for producing a current map









Compressed sensing: Application on PV characterisation

- Every row of Φ is a binary random pattern that will be projected on the sample, measuring the current response.
- The patterns and the image are represented in a vector form
- m measurements to measure the K necessary coefficients for a successful reconstruction K<<m< $n=\sqrt{N}$ $x\sqrt{N}$



Random binary pattern

m measurements

 $\mathbf{y} = \begin{bmatrix} y_1 \\ y_2 \\ y_i \\ y_m \end{bmatrix}$

Reconstruction using $\ell1$ minimisation

solution

$$\hat{x} = \begin{bmatrix} x_1 \\ x_2 \\ x_i \\ x_n \end{bmatrix}$$

Measurement vector

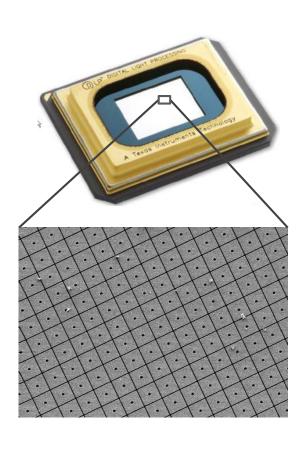
Unknown







Digital Micromirror Device – DMD Pattern generator



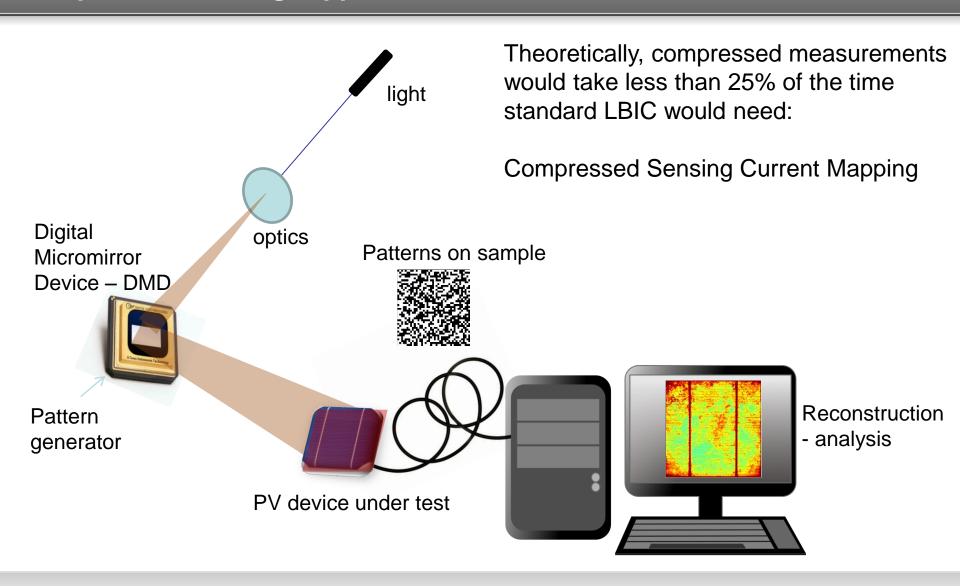
- Array of microscopic mirrors
- +12° / -12° mirror state On/Off
- Aluminium micromirror ~10µmx10µm (size)
- Response time: ~16 µs very fast sampling can be achieved
- Resolution:
- from 800x600 up to1920x1080 pixels







Compressed sensing: Application on PV characterisation

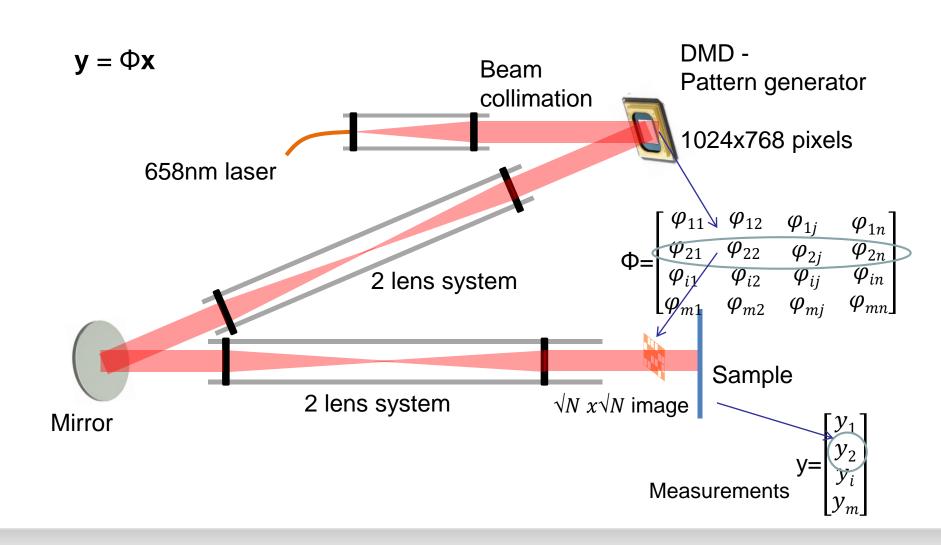








Prototype setup in NPL

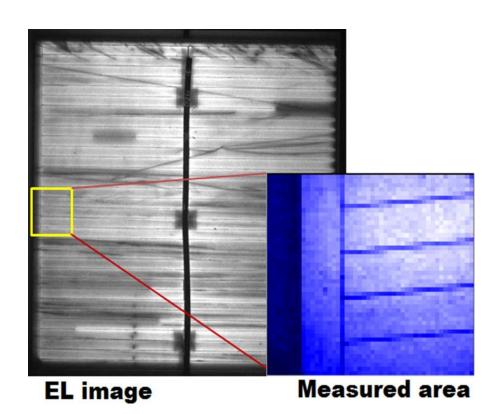








- Ribbon mc-Si cells were encapsulated and characterised in CREST
- CS-LBIC measurements with the experimental setup in NPL.
- The CS-LBIC experimental setup can currently only scan a small area of the cell 1cmx1cm
- Small distortion of reconstructed image due to misalignment of the projection plane
- Non uniform irradiance on the sample

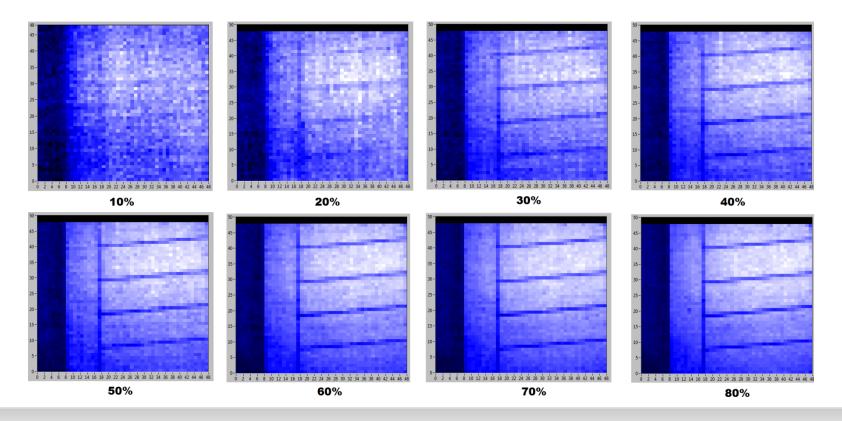








- Number of measurements is expressed as a percentage of the image's pixels (in reality this is the number of measurements a raster scan would need)
- Using a 658nm laser source no defects are visible
- 48x48 current map (2304 pixels) 160µm resolution

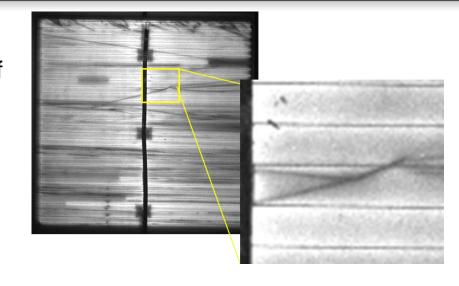


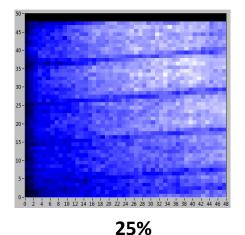


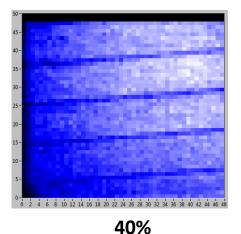


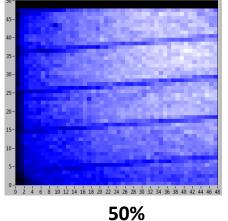


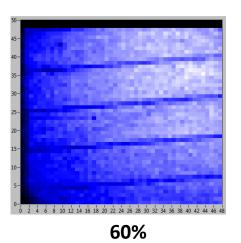
- Using a 785nm laser source on an area of the sample that contains a crack
- 48x48 current map 160µm resolution









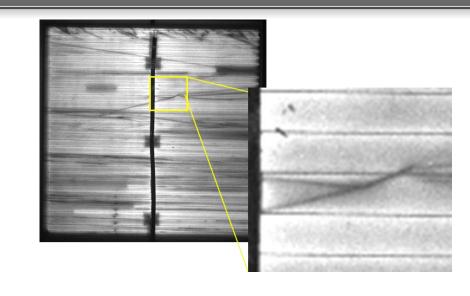


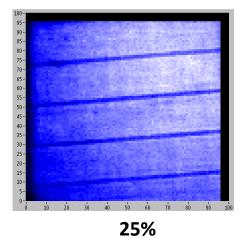


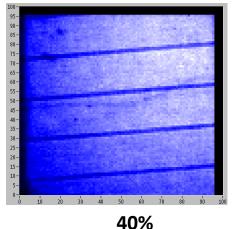


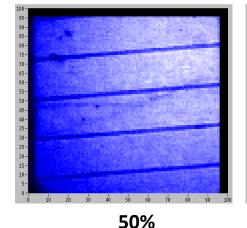


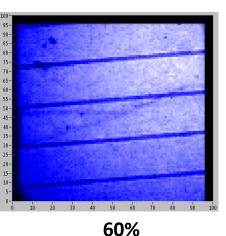
- 785nm laser
- 96x96 current map (9216 pixels) 80μm resolution
- Defects are clearly visible, even with the current non-uniform irradiance on the sample

















Conclusions

- Compressed sensing theory applied for current mapping of PV devices
- CS-LBIC measurements are feasible prototype measurement setup demonstrated
- Fewer measurements and the very fast response of the DMD kit can result in faster current mapping comparing to standard LBIC systems
- Still in development Optimised version of the experimental setup will provide more accurate results.

Thank you for your attention



